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(54) Title (EN): ANALYSIS METHOD AND ANALYSIS DEVICE

(54) Title (FR): PROCÉDÉ ET DISPOSITIF D'ANALYSE

(54) Title (JA): 分析方法及び分析装置

(57) Abstract:

(EN): Laser light (50a) is irradiated on an analysis substrate (1), reflected light from a reaction region (10) is received, and a light reception level signal (JS) is generated. Furthermore, in the reaction region (10), a light reception level signal (JS) having a signal level higher than a prescribed signal level (Lth) is extracted as a particle detection signal (KS), and a substance to be detected (11) is detected on the basis of the extracted particle detection signal (KS). The analysis substrate (1) has: the reaction region (10) on which are captured first particles (20) provided with the substance to be detected (11) and antibodies (21) that recognize the substance to be detected (11), and second particles (30) provided with an antigen (31) that bonds with the antibodies (21), the second particles (30) being formed from a metal; and a non-reaction region (9) on which the reaction region (10) is not formed. The analysis substrate (1) is formed of a resin material.

(FR): L'invention se rapporte à une lumière laser (50a) qui est irradiée sur un substrat d'analyse (1), la lumière réfléchie provenant d'une région de réaction (10) est reçue et un signal de niveau de réception de lumière (JS) est généré. De plus, dans la région de réaction (10), un signal de niveau de réception de lumière (JS) ayant un niveau de signal supérieur à un niveau de signal prescrit (Lth) est extrait en tant que signal de détection de particules (KS), et une substance à détecter (11) est détectée sur la base du signal de détection de particules extrait (KS). Le substrat d'analyse (1) comprend : la région de réaction (10) sur laquelle sont capturées des premières particules (20) fournies avec la substance à détecter (11) et des anticorps (21) qui reconnaissent la substance à détecter (11), et des deuxièmes particules (30) pourvues d'un antigène (31) qui se lie aux anticorps (21), les deuxièmes particules

(30) étant formées à partir d'un métal ; et une région de non-réaction (9) sur laquelle la région de réaction (10) n'est pas formée. Le substrat d'analyse (1) est formé d'un matériau de résine.

(JA): 分析用基板(1)にレーザー光(50a)が照射され、反応領域(10)からの反射光を受光して受光レベル信号(JS)が生成される。さらに、反応領域(10)において所定の信号レベル(Lth)よりも高い信号レベルの受光レベル信号(JS)が粒子検出信号(KS)として抽出され、抽出された粒子検出信号(KS)に基づいて検出対象物質(11)が検出される。分析用基板(1)は、検出対象物質(11)と、検出対象物質(11)を認識する抗体(21)が設けられた第1粒子(20)と、抗体(21)と結合する抗原(31)が設けられ、金属により形成された第2粒子(30)とが捕捉された反応領域(10)と、反応領域(10)が形成されていない未反応領域(9)と、を有し、樹脂材料で形成される。

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